

PROPOSED AMENDMENTS FOR DISCUSSION ONLY

AMENDMENTS TO THE SPECIFICATION

Please replace the paragraph beginning at page 22, line 14, with the following rewritten paragraph:

Shape coefficients SF-1 and SF-2 are sphericity factors for the present invention, which are measured as follows. An S-4200 field emission scanning electron microscope (Hitachi Ltd.) is used to obtain SEM images of toner particles. Then, 300 images are randomly selected, and the information of the images is introduced to a Luzex AP image analyzer (Nireco Corporation) through an interface and analyzed by the device. Then, using the following formulae, SF-1 and SF-2 are defined. It is preferred that SF-1 and SF-2 are measured using a Luzex analyzer, but as far as the same analysis can be made, devices being used are not limited to the above-mentioned FESEM and image analyzer.

$$SF-1 = (\frac{L^2}{A}) \times (\pi/4) \times 100$$

$$SF-1 = (\frac{P^2}{A}) \times (\pi/4) \times 100$$

where "L" is the absolute maximum length of a toner particle, "A" is the projected area of a toner, and "P" is the maximum perimeter of a toner.